

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/727,311	HAN ET AL.	
	Examiner	Art Unit	
	Hiep T. Nguyen	2187	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
PG -	pub	Text search.	
		7/24/06	HN